

LIST OF REFERENCES CITED BY APPLICANT
(Use several sheets if necessary)

ATTY. DOCKET NO.:	APPLICATION SERIAL NO.:
4717-8500	10/764, 289
APPLICANT:	
Bruno GHYSELEN et al.	

FILING DATE:	GROUP:
January 23, 2004	2812

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Dle	AA	5,882,987	3/1999	Srikrishnan	438	458	
	AB	6,284,628 B1	9/2001	Kuwahara et al.	438	459	
	AC	6,306,729 B1	10/2001	Sakaguchi et al..	438	458	
	AD	6,326,279 B1	12/2001	Kakizaki et al.	438	406	
	AE	6,375,738	4/2002	Sato	117	89	
	AF	6,468,923 B1	12/2002	Yonehara et al.	438	761	
Dle	AG	2002/0072130 A1	6/2002	Cheng et al.	438	10	

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							YES NO
Dle	AH	EP 0 955 671 A1	11/1999	Europe			X
	AI	EP 1 039 513 A2	9/2000	Europe			X
	AJ	EP 0 926 709 A2	6/1999	Europe			X
	AK	EP 1006 567 A2	6/2000	Europe			X
	AL	EP 0 849 788 A2		Europe			X
	AM	WO 01/11930 A2	2/2001	PCT			X
Dle	AN	WO 99/53539	10/1999	PCT			X

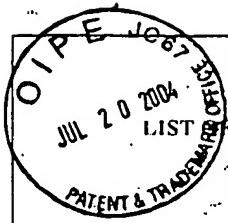
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Dle	AO	L. J. Huang et al, "SiGe-on-insulator prepared by wafer bonding and layer transfer for high-performance field-effect transistors", Applied Physics Letters, Vol. 78, No. 9, pp. 1267-1269 (2001)
	AP	Q. Y. Tong et al "Extracts of "Semi-conductor on wafer bonding", Science and Technology, Interscience Technology, Wiley Interscience publication, Johnson Wiley & Sons, Inc.
	AQ	

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Dh	AA	2001/0029072 A1	10/2001	Kuwahara et al.	438	151	
	AB	2001/0003269 A1	6/2001	Wu et al.	117	94	
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	AK						
	AL						
	AM						
	AN						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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